

ZXMN3F31DN8 30V SO8 dual N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)
30	0.024 @ V _{GS} = 10V	7.3
	0.039 @ V _{GS} = 4.5V	5.7



Description

This new generation Trench MOSFET from Zetex features low onresistance achievable with 4.5V gate drive.

Features

- Low on-resistance
- 4.5V gate drive capability

Applications

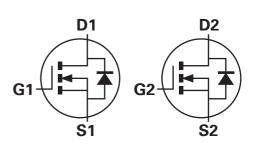
- DC-DC Converters
- Power management functions
- Load switching
- Motor control
- Back lighting

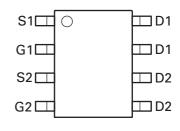
Ordering information

DEVICE	Reel size	Tape width	Quantity	
	(inches)	(mm)	per reel	
ZXMN3F31DN8TA	7	12	500	

Device marking

ZXMN 3F31D





Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain source voltage	V _{DSS}	30	V
Gate source voltage	V _{GS}	±20	V
Continous Drain Current @ V _{GS} =10; T _A =25°C ^(b)	۱ _D	7.3	А
@ V _{GS} =10; T _A =70°C ^(b)		5.9	А
@ V _{GS} =10; T _A =25°C ^(a)		5.7	А
Pulsed drain current ^(c)	I _{DM}	33	А
Continuous source current (body diode) ^(b)	۱ _S	3.5	А
Pulsed source current (body diode) ^(c)	I _{SM}	33	А
Power dissipation at $T_A = 25^{\circ}C^{(a)(d)}$	PD	1.25	W
Linear derating factor		10	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(a)(e)}$	PD	1.8	W
Linear derating factor		14	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(b)(d)}$	PD	2.1	W
Linear derating factor		17	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^{(a)(d)}	R _{OJA}	100	°C/W
Junction to ambient ^{(a)(e)}	R _{OJA}	70	°C/W
Junction to ambient ^{(b)(d)}	R _{OJA}	60	°C/W
Junction to lead ^(f)	R _{ƏJL}	53	°C/W

NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t \leq 10 sec.

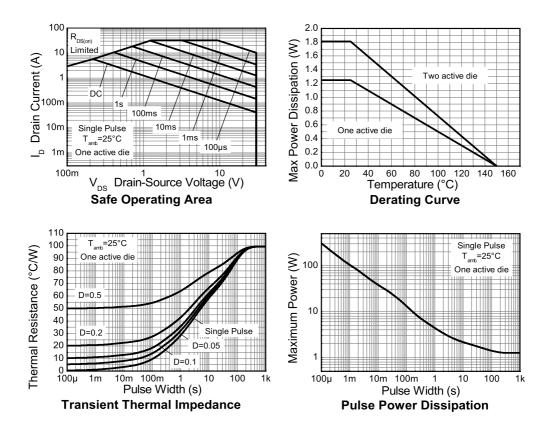
(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300μs - pulse width limited by maximum junction temperature.

(d) For a dual device with one active die.

(e) For a device with two active die running at equal power.

(f) Thermal resistance from junction to solder-point (at end of drain lead).

Thermal characteristics



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions	
Static							
Drain-Source breakdown voltage	V _{(BR)DSS}	30			V	I _D = 250μA, V _{GS} =0V	
Zero Gate voltage drain current	I _{DSS}			0.5	μA	V _{DS} = 30V, V _{GS} =0V	
Gate-Body leakage	I _{GSS}			100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$	
Gate-Source threshold voltage	V _{GS(th)}	1.0		3.0	V	I_D = 250 μ A, V_{DS} = V_{GS}	
Static Drain-Source on-state resistance ^(*)	R _{DS(on)}			0.024 0.039	Ω Ω	V _{GS} = 10V, I _D = 7.0A V _{GS} = 4.5V, I _D = 6.0A	
Forward transconductance ^{(*)(†)}	9 _{fs}		16.5		S	V _{DS} = 15V, I _D = 7A	
Dynamic ^(†)			1				
Input capacitance	C _{iss}		608		pF		
Output capacitance	C _{oss}		132		pF	V _{DS} = 15V, V _{GS} =0V _ f=1MHz	
Reverse transfer capacitance	C _{rss}		71		pF		
Switching ^{(‡)(†)}							
Turn-on-delay time	t _{d(on)}		2.9		ns		
Rise time	t _r		3.3		ns	V _{DD} = 15V, I _D = 1A R _G ≅ 6.0Ω, V _{GS} =10V	
Turn-off delay time	t _{d(off)}		16		ns	-11G = 0.032, VGS - 10V	
Fall time	t _f		8		ns		
Total gate charge	Qg		12.9		nC	V _{DS} = 15V, V _{GS} = 10V	
Gate-source charge	Q _{gs}		2.5		nC	I _D = 7A	
Gate drain charge	0 _{gd}		2.52		nC		
Source-drain diode	· · · · ·		•				
Diode Forward Voltage ^(*)	V _{SD}		0.82	1.2	V	T _j =25°C, I _S = 1.7A, V _{GS} =0V	
Reverse recovery time ^(†)	t _{rr}		12		ns	T _j =25°C, I _S =2.2A	
Reverse recovery charge ^(†)			4.8		nC	di/dt=100A/µs	

Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

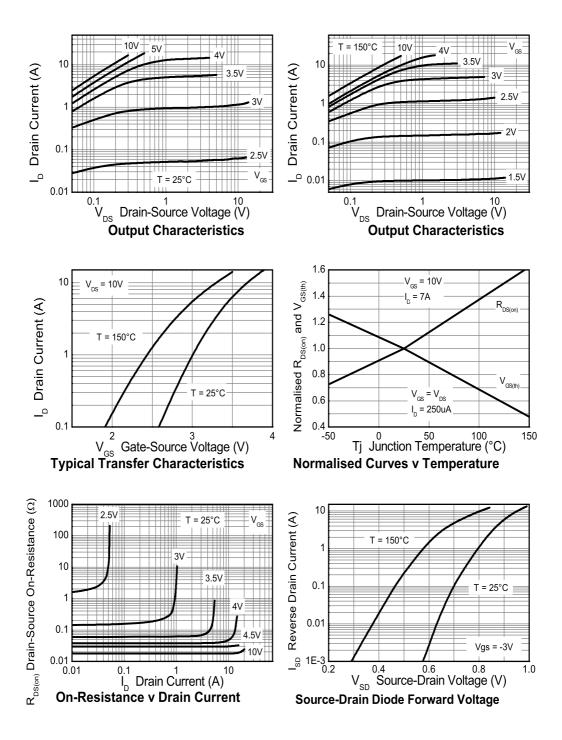
NOTES:

(*) Measured under pulsed conditions. Pulse width \leq 300µs; duty cycle \leq 2%.

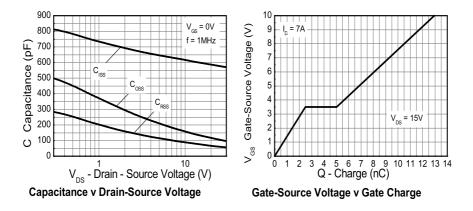
(†) For design aid only, not subject to production testing

(‡) Switching characteristics are independent of operating junction temperature.

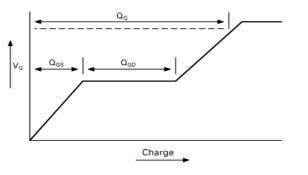
Typical characteristics



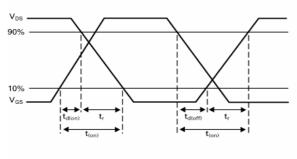
Typical characteristics



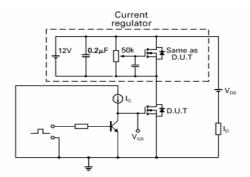
Test circuits



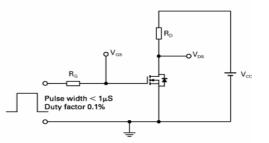
Basic gate charge waveform



Switching time waveforms

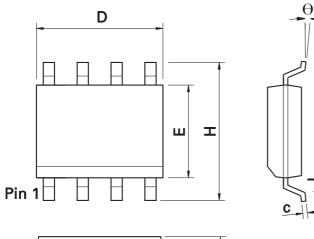


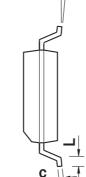
Gate charge test circuit

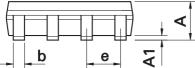


Switching time test circuit

Package outline - SO8







Seating Plane

DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
А	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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